


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564475	<b>Applicant(s)/Patent Under Reexamination</b>  GRUDIN ET AL.
	<b>Examiner</b>  THIEM PHAN	<b>Art Unit</b>  3729

SEARCHED			
Class	Subclass	Date	Examiner
29	610.1, 592.1, 612, 620, 825, 829	3/02/09	TP
219	494, 505	"	"
257	538, 539, E27.047	"	"
338	195, 320	"	"
438	238, 382	"	"

SEARCH NOTES		
Search Notes	Date	Examiner
UpdatedEAST Search Attached	3/02/09	TP
Keywords: (trimm\$3 with (resistor or impedance or resistance or resistivity)) same (hysteresis) and ((measur\$3 or read\$3 or record\$3 or display\$3) near4 output)	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
29	610.1, 620, 825	3/02/09	TP
257	538, E27.047	"	"
338	195, 320	"	"

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